

Microbeam analysis — Electron probe microanalysis — Quantitative point analysis for bulk specimens using wavelength-dispersive X-ray spectroscopy

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National foreword

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A list of organizations represented on CII/9 can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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Microbeam analysis — Electron probe microanalysis — Quantitative point analysis for bulk specimens using wavelength-dispersive X-ray spectroscopy

*Analyse par microfaisceaux — Analyse par microsonde de Castaing —
Analyse quantitative ponctuelle d'échantillons massifs par spectrométrie
X à dispersion de longueur d'onde*



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Foreword

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ISO 22489 was prepared by Technical Committee ISO/TC 202, *Microbeam analysis*, Subcommittee SC 2, *Electron probe microanalysis*.

Introduction

Electron microanalysis is widely used for the quantitative analysis of elemental composition in materials. It is a typical instrumental analysis and the electron probe microanalyser has been greatly improved to be user-friendly. Obtaining accurate results with this powerful tool requires that it be properly used. In order to obtain reliable data, however, optimum procedures must be followed. These procedures, such as preparation of specimens, measurement of intensities of characteristic X-rays and calculation of concentrations from X-ray intensities, are given, for use as standard procedures, in this International Standard.

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